

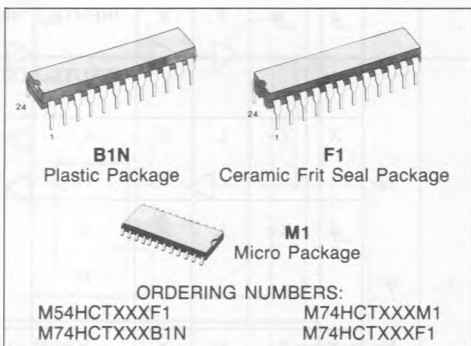


**HCT646 OCTAL BUS TRANSCEIVER/REGISTER (3-STATE)**  
**HCT648 OCTAL BUS TRANSCEIVER/REGISTER (INVERTING-3 STATE)**

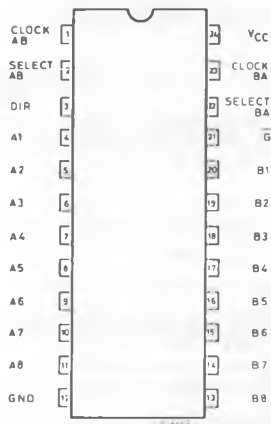
- **LOW POWER DISSIPATION**  
 $I_{CC} = 4\mu A$  (MAX.) at  $T_A = 25^\circ C$
- **COMPATIBLE WITH TTL OUTPUTS**  
 $V_{IH} = 2V$  (MIN)  $V_{IL} = 0.8V$  (MAX.)
- **OUTPUT DRIVE CAPABILITY**  
15 LSTTL LOADS
- **SYMMETRICAL OUTPUT IMPEDANCE**  
 $|I_{OL}| = I_{OL} = 6mA$  (MIN.)
- **BALANCED PROPAGATION DELAYS**  
 $t_{PLH} = t_{PHL}$
- **PIN AND FUNCTION COMPATIBLE**  
WITH 54/74LS646/648

**DESCRIPTION**

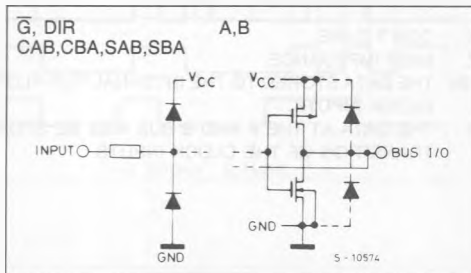
The M54/74HCT646/648 are high speed CMOS OCTAL BUS TRANSCEIVERS and REGISTERS, (3-STATE), fabricated in silicon gate C<sup>2</sup>MOS technology. They have the same high speed performance of LSTTL, combined with true CMOS low power consumption. These devices consist of bus transceiver circuits with 3-state output, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the input bus or from the internal registers. Data on the "A" or "B" bus will be clocked into the registers on the low-to-high transition of the appropriate clock pin (Clock AB - or Clock BA). Enable ( $\bar{G}$ ) and direction (DIR) pins are provided to control the transceiver functions. In the transceiver mode, data present at the high-impedance port may be stored in either register or in both. The select controls (Select AB Select BA) can multiplex stored and real-time (transparent mode) data. The direction control determines which bus will receive data when the enable  $\bar{G}$  is active (low). In the isolation mode (enable  $\bar{G}$  high), "A" data may be stored in one register and/or "B" data may be stored in the other register. When an output function is disabled, the input function is still enabled and may be used to store and transmit data. Only one of the two buses, A or B, may be driven at a time. All inputs are equipped with protection circuits against static discharge and transient excess voltage. These integrated circuit have totally compatible, input and output characteristics, with standard 54/74 LSTTL logic families. M54HCT/74HCT devices are designed to directly interface HSC<sup>2</sup> MOS systems with TTL and NMOS components. These devices are also plug in replacements for LSTTL devices giving a reduction in power consumption.



**PIN CONNECTIONS (top view)**



**INPUT AND OUTPUT EQUIVALENT CIRCUIT**



**TRUTH TABLE**

M54/74HCT646 (The truth table for M54/74HCT648 is the same as this, but with the outputs inverted)

$\bar{G}$	DIR	CAB	CBA	SAB	SBA	A	B	FUNCTION
H	X					INPUTS	INPUTS	Both the A bus and the B bus are inputs.
		X	X	X	X	Z	Z	The output functions of the A and B bus are disabled.
				X	X	INPUTS	INPUTS	Both the A and B bus are used for inputs to the internal flip-flops. Data at the bus will be stored on low to high transition of the clock inputs.
L	H					INPUTS	OUTPUTS	The A bus are inputs and the B bus are outputs.
		X	X*	L	X	L H	L H	The data at the A bus are displayed at the B bus.
			X*	L	X	L H	L H	The data at the A bus are displayed at the B bus. The data of A bus are stored to the internal flip-flops on low to high transition of the clock pulse.
		X	X*	H	X	X	Qn	The data stored to the internal flip-flops are displayed at the B bus.
			X*	H	X	L H	L H	The data at the A bus are stored to the internal flip-flops on low to high transition of the clock pulse. The states of the internal flip-flops output directly to the B bus
L	L					OUTPUTS	OUTPUTS	The B bus are inputs and the A bus are outputs.
		X*	X	X	L	L H	L H	The data at the B bus are displayed at the A bus.
		X*		X	L	L H	L H	The data at the B bus are displayed at the A bus. The data of B bus are stored to the internal flip-flops on low to high transition of the clock pulse.
		X*	X	X	H	Qn	X	The data stored to the internal flip-flops are displayed at the B bus.
		X*		X	H	L H	L H	The data at the B bus are stored to the internal flip-flops on low to high transition of the clock pulse. The states of the internal flip-flops output directly to the A bus.

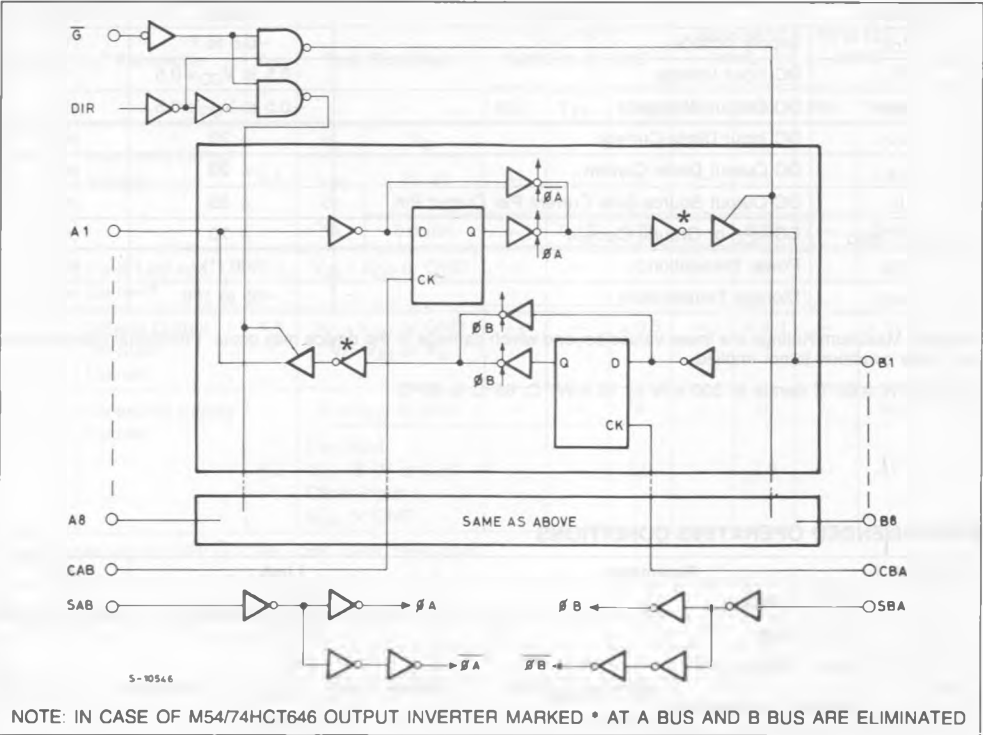
X : DON'T CARE.

Z : HIGH IMPEDANCE.

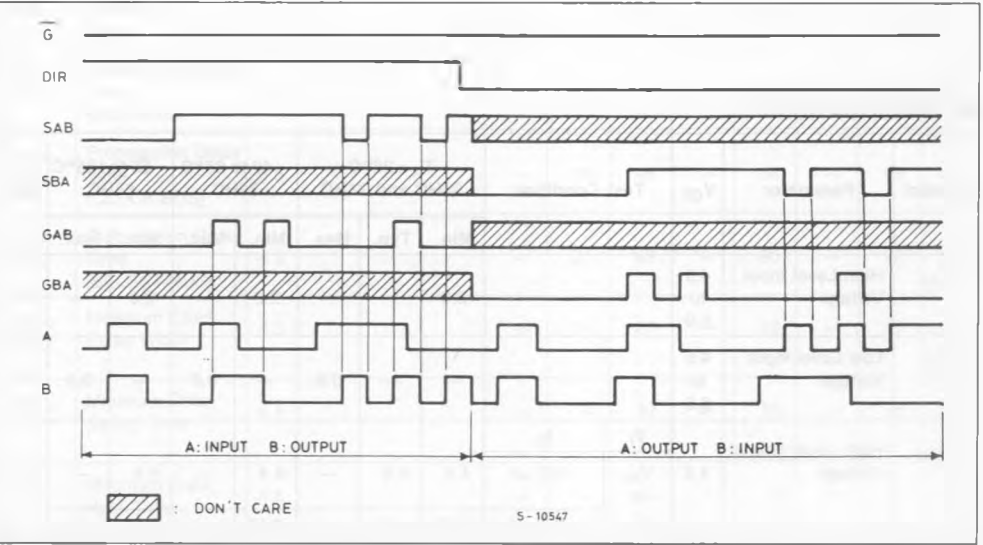
QN: THE DATA STORED TO THE INTERNAL FLIP-FLOPS BY MOST RECENT LOW TO HIGH TRANSITION OF THE CLOCK INPUTS.

\* : THE DATA AT THE A AND B BUS WILL BE STORED TO THE INTERNAL FLIP-FLOPS ON EVERY LOW TO HIGH TRANSITION OF THE CLOCK INPUTS.

LOGIC DIAGRAM (HCT648)



TIMING CHART



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Supply Voltage	– 0.5 to 7	V
V <sub>I</sub>	DC Input Voltage	– 0.5 to V <sub>CC</sub> + 0.5	V
V <sub>O</sub>	DC Output Voltage	– 0.5 to V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	DC Input Diode Current	± 20	mA
I <sub>OK</sub>	DC Output Diode Current	± 20	mA
I <sub>O</sub>	DC Output Source Sink Current Per Output Pin	± 35	mA
I <sub>CC</sub> or I <sub>GND</sub>	DC V <sub>CC</sub> or Ground Current	± 70	mA
P <sub>D</sub>	Power Dissipation	500 (*)	mW
T <sub>stg</sub>	Storage Temperature	– 65 to 150	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these condition is not implied.

(\*) 500 mW: ≡ 65°C derate to 300 mW by 10 mW/°C: 65°C to 85°C

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Limit	Unit
V <sub>CC</sub>	Supply Voltage	4.5 to 5.5	V
V <sub>I</sub>	Input Voltage	0 to V <sub>CC</sub>	V
V <sub>O</sub>	Output Voltage	0 to V <sub>CC</sub>	V
T <sub>A</sub>	Operating Temperature 74HC Series 54HC Series	– 40 to 85 – 55 to 125	°C
t <sub>r</sub> , t <sub>f</sub>	Input Rise and Fall Time	0 to 500	ns

DC SPECIFICATIONS

Symbol	Parameter	V <sub>CC</sub>	Test Condition	T <sub>A</sub> = 25°C 54HC and 74HC			– 40 to 85°C 74HC		– 55 to 125°C 54HC		Unit
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
V <sub>IH</sub>	High Level Input Voltage	4.5 to 6.0		2.0	—	—	2.0	—	2.0	—	V
V <sub>IL</sub>	Low Level Input Voltage	4.5 to 5.5		—	—	0.8	—	0.8	—	0.8	V
V <sub>OH</sub>	High Level Output Voltage	4.5	V <sub>I</sub>	4.4	4.5	—	4.4	—	4.4	—	V
			V <sub>IH</sub> or V <sub>IL</sub>								
			– 20 µA								
			– 6.0 mA	4.18	4.31	—	4.13	—	4.10	—	

## DC SPECIFICATIONS (Continued)

Symbol	Parameter	V <sub>CC</sub>	Test Condition		T <sub>A</sub> = 25°C 54HC and 74HC			– 40 to 85°C 74HC		– 55 to 125°C 54HC		Unit
					Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
V <sub>OL</sub>	Low Level Output Voltage	4.5	V <sub>I</sub>	I <sub>O</sub>	—	0	0.1	—	0.1	—	0.1	V
			V <sub>IH</sub> or V <sub>IL</sub>	20 µA								
				6.0 mA								
I <sub>IN</sub>	Input Leakage Current*	5.5	V <sub>IN</sub> = V <sub>CC</sub> or GND		—	—	±0.1	—	±1	—	±1	µA
I <sub>OZ</sub>	3-State Output Off-State Current	4.5	V <sub>O</sub> = V <sub>CC</sub> or GND V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>		—	—	±0.5	—	±5.0	—	±10.0	
I <sub>CC</sub>	Quiescent Supply Current	5.5	V <sub>I</sub> = V <sub>CC</sub> or GND		—	—	4	—	40	—	80	µA
I <sub>CC</sub>			Per input: V <sub>IN</sub> = 2.4V or 0.5V Other input: V <sub>CC</sub> or GND		—	—	2.0	—	2.9	—	3.0	mA

\*: Applicable only to DIR,  $\overline{G}$ , CAB, CBA, SAB, SBA input.AC ELECTRICAL CHARACTERISTICS (C<sub>L</sub> = 50pF, Input t<sub>r</sub> = t<sub>f</sub> = 6ns)

Symbol	Parameter	V <sub>CC</sub>	Test Condition	T <sub>A</sub> = 25°C 54HC and 74HC			– 40 to 85°C 74HC		– 55 to 125°C 54HC		Unit
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
t <sub>TLH</sub> t <sub>THL</sub>	Output Transition Time	4.5		—	7	12	—	15	—	18	ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay Time (BUS-BUS)	4.5		—	20	31	—	39	—	47	ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay Time (CLOCK-BUS)	4.5		—	30	46	—	58	—	69	ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay Time (SELECT-BUS)	4.5		—	31	48	—	60	—	72	ns
t <sub>W(H)</sub> t <sub>W(L)</sub>	Minimum Clock Pulse Width	4.5		—	11	20	—	25	—	30	ns
t <sub>s</sub>	Minimum Data Set-up Time	4.5		—	4	10	—	13	—	15	ns
t <sub>h</sub>	Minimum Data Hold Time	4.5		—	—	5	—	5	—	5	ns

AC ELECTRICAL CHARACTERISTICS (Continued)

Symbol	Parameter	V <sub>CC</sub>	Test Condition	T <sub>A</sub> = 25°C 54HC and 74HC			- 40 to 85°C 74HC		- 55 to 125°C 54HC		Unit
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
t <sub>PZL</sub> t <sub>PZH</sub>	3-State Output Enable Time ( $\bar{G}$ , BUS)	4.5	R <sub>L</sub> = 1k $\Omega$	—	26	38	—	48	—	57	ns
t <sub>PLZ</sub> t <sub>PHZ</sub>	3-State Output Disable Time ( $\bar{G}$ , BUS)	4.5	R <sub>L</sub> = 1k $\Omega$	—	26	38	—	48	—	57	ns
t <sub>PZL</sub> t <sub>PZH</sub>	3-State Output Enable Time (DIR- BUS)	4.5	R <sub>L</sub> = 1k $\Omega$	—	28	40	—	50	—	60	ns
t <sub>PLZ</sub> t <sub>PHZ</sub>	3-State Output Disable Time (DIR-BUS)	4.5	R <sub>L</sub> = 1k $\Omega$	—	28	40	—	50	—	60	ns
C <sub>IN</sub>	Input Capacitance		*	—	5	10	—	10	—	10	pF
C <sub>OUT</sub>	Output Capacitance		A <sub>n</sub> , B <sub>n</sub>	—	13	—	—	—	—	—	pF
C <sub>PD</sub> (1)	Power Dissipation Capacitance		HCT646	—	55	—	—	—	—	—	pF
			HCT648	—	52	—	—	—	—	—	

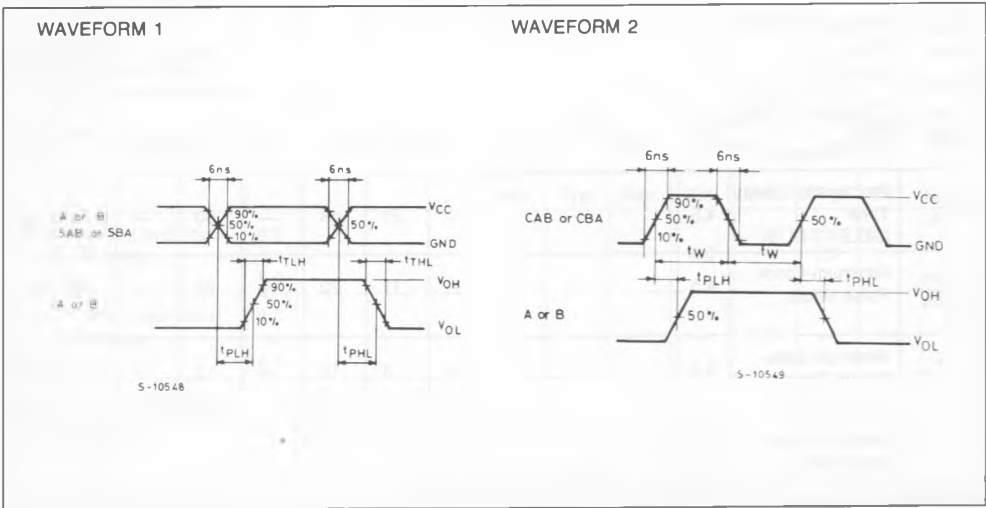
\*: Applicable only to DIR,  $\bar{G}$ , CAB, CBA, SAB, SBA input.

Note (1): C<sub>PD</sub> is defined as the value of internal equivalent capacitance of IC which is calculated from the operating current consumption without load (refer to Test circuit).

Average operating current can be obtained from the equation hereunder.

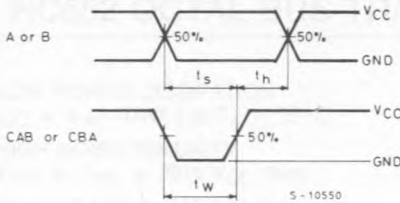
$$I_{CC(opr.)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8 \text{ (per bit)}$$

SWITCHING CHARACTERISTICS TEST WAVEFORM

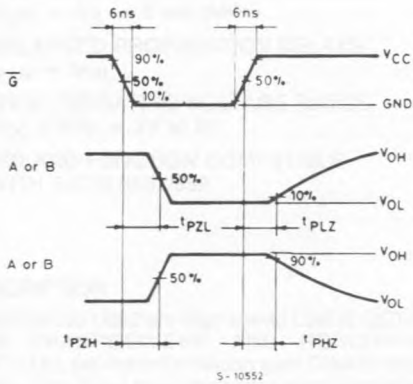


## SWITCHING CHARACTERISTICS TEST WAVEFORM (Continued)

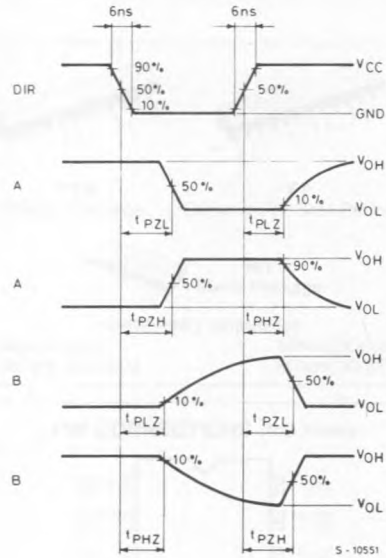
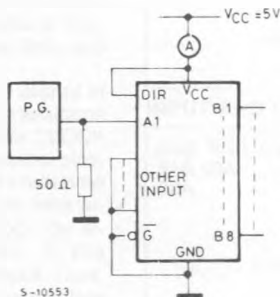
WAVEFORM 3



WAVEFORM 4



WAVEFORM 5

TEST CIRCUIT  $I_{CC}$  (Opr.)

INPUT TRANSITION TIME IS THE SAME AS THAT IN CASE OF SWITCHING CHARACTERISTICS TEST